ECOSPARK® Ignition IGBT

300 mJ, 400 V, N-Channel Ignition IGBT

Features

- SCIS Energy = 300 mJ at $T_J = 25$ °C
- Logic Level Gate Drive
- This Device is Pb-Free and is RoHS Compliant
- AEC-Q101 Qualified and PPAP Capable

Applications

- Automotive Ignition Coil Driver Circuits
- High Current Ignition System
- Coil on Plug Applications

MAXIMUM RATINGS ($T_J = 25^{\circ}C$ Unless Otherwise Stated)

Parameter	Symbol	Value	Units
Collector to Emitter Breakdown Voltage (I _C = 1 mA)	BV _{CER}	400	V
Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10 mA)	BV _{ECS}	24	V
ISCIS = 14.2 A, L = 3.0 mHz, R _{GE} = 1 K Ω (Note 1), T _C = 25°C	E _{SCIS25}	300	mJ
$\begin{array}{l} \text{ISCIS} = 10.6 \text{ A, L} = 3.0 \text{ mHz,} \\ \text{R}_{\text{GE}} = 1 \text{ K}\Omega \text{ (Note 2), T}_{\text{C}} = 150^{\circ}\text{C} \end{array}$	E _{SCIS150}	170	mJ
Collector Current Continuous, at V _{GE} = 4.0 V, T _C = 25°C	IC25	21	Α
Collector Current Continuous, at V _{GE} = 4.0 V, T _C = 110°C	IC110	17	Α
Gate to Emitter Voltage Continuous	V_{GEM}	±10	V
Power Dissipation Total, T _C = 25°C	PD	150	W
Power Dissipation Derating, T _C > 25°C	PD	1	W/°C
Operating Junction and Storage Temperature	T _J , T _{STG}	–55 to 175	°C
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)	TL	300	°C
Reflow soldering according to JESD020C	T _{PKG}	260	°C
HBM-Electrostatic Discharge Voltage at100 pF, 1500 Ω	ESD	4	kV
CDM–Electrostatic Discharge Voltage at 1 Ω	ESD	2	kV

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

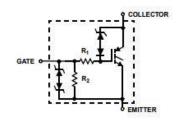
- Self Clamped inductive Switching Energy (ESCIS25) of 300 mJ is based on the test conditions that is starting T_J = 25°C, L = 3 mHz, ISCIS = 14.2 A, V_{CC} = 100 V during inductor charging and V_{CC} = 0 V during time in clamp.
- 2. Self Clamped inductive Switching Energy (ESCIS150) of 170 mJ is based on the test conditions that is starting $T_J = 150^{\circ}C$, L = 3 mHz, ISCIS = 10.6 A, $V_{CC} = 100$ V during inductor charging and $V_{CC} = 0$ V during time in clamp.

1



ON Semiconductor®

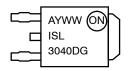
www.onsemi.com





DPAK (SINGLE GAUGE) CASE 369C

MARKING DIAGRAM



ISL3040DG = Device Code A = Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

THERMAL RESISTANCE RATINGS

Characteristic	Symbol	Max	Units
Junction-to-Case - Steady State (Drain) (Notes 1, 3 and 4)	$R_{ heta JC}$	1	°C/W

ELECTRICAL CHARACTERISTICS (T_J = 25°C Unless Otherwise Specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS	•						
Collector to Emitter Breakdown Voltage	BV _{CER}	$I_{CE} = 2 \text{ mA}, V_{GE} = 0 \text{ V},$ $R_{GE} = 1 \text{ K}\Omega,$ $T_{J} = -40 \text{ to } 150^{\circ}\text{C}$		370	400	430	V
Collector to Emitter Breakdown Voltage	BV _{CES}	$I_{CE} = 10 \text{ mA}, V_{GE} = 0 \text{ N}$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to } 150^{\circ}\text{C}$	V,	390	420	450	V
Emitter to Collector Breakdown Voltage	BV _{ECS}	$I_{CE} = -75 \text{ mA}, V_{GE} = 0$ $T_{J} = 25^{\circ}\text{C}$	V,	30	-	-	V
Gate to Emitter Breakdown Voltage	BV _{GES}	I _{GES} = ±2 mA		±12	±14	-	V
Collector to Emitter Leakage Current	I _{CER}	V _{CE} = 175 V,	T _J = 25°C	-	-	25	μΑ
		$R_{GE} = 1 K\Omega$	T _J = 150°C	_	-	1	mA
Emitter to Collector Leakage Current	I _{ECS}	V _{EC} = 24 V	T _J = 25°C	_	_	1	mA
			T _J = 150°C	_	-	40	
Series Gate Resistance	R ₁			_	70	-	Ω
Gate to Emitter Resistance	R ₂			10 K	-	26 K	Ω
ON CHARACTERISTICS							
Collector to Emitter Saturation Voltage	V _{CE(SAT)}	I _{CE} = 6 A, V _{GE} = 4 V T _J = 25°C		-	1.25	1.65	V
Collector to Emitter Saturation Voltage	V _{CE(SAT)}	I _{CE} = 10 A, V _{GE} = 4.5 \ T _J = 150°C	/	_	1.58	1.80	V
Collector to Emitter Saturation Voltage	V _{CE(SAT)}	I _{CE} = 15 A, V _{GE} = 4.5 \ T _J = 150°C	/	-	1.90	2.20	V
OYNAMIC CHARACTERISTICS							
Gate Charge	Q _{G(ON)}	I _{CE} = 10 A, V _{CE} = 12 V	′, V _{GE} = 5 V	-	17	-	nC
Gate to Emitter Threshold Voltage	V _{GE(TH)}	I _{CE} = 1 mA,	T _J = 25°C	1.3	-	2.2	V
		V _{CE} = V _{GE}	T _J = 150°C	0.75	-	1.8	
Gate to Emitter Plateau Voltage	V_{GEP}	V _{CE} = 12 V, I _{CE} = 10 A		-	3.0	-	V
WITCHING CHARACTERISTICS							
Current Turn-On Delay Time-Resistive	td _{(ON)R}	$V_{CE} = 14 \text{ V}, R_{L} = 1 \Omega$ $V_{GE} = 5 \text{ V}, R_{G} = 470 \Omega$ $T_{J} = 25^{\circ}\text{C}$		-	0.7	4	μs
Current Rise Time-Resistive	t _{rR}			-	2.1	7	
Current Turn-Off Delay Time-Inductive	td _{(OFF)L}	V _{CE} = 300 V, L = 1 mH,		-	4.8	15	
Current Fall Time-Inductive	tfL	$V_{GE} = 5 \text{ V}, R_{G} = 470 \Omega$ $I_{CE} = 6.5 \text{ A}, T_{J} = 25^{\circ}\text{C}$		-	2.8	15	

PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Reel Diameter	Tape Width	Qty
ISL9V3040G1	ISL9V3040D3STV	DPAK (Pb-Free)	330 mm	16 mm	2500

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

TYPICAL CHARACTERISTICS

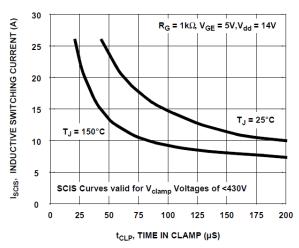


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

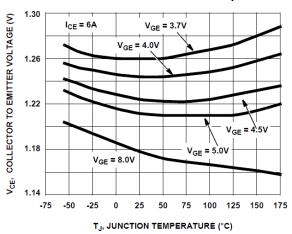


Figure 3. Collector to Emitter On–State Voltage vs. Junction Temperature

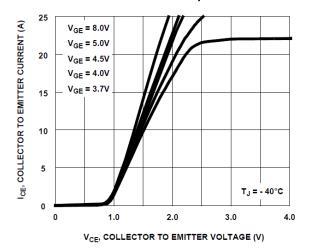


Figure 5. Collector to Emitter On–State Voltage vs. Collector Current

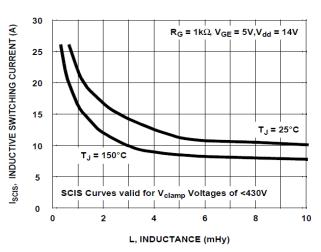


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

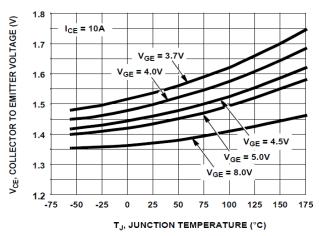


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

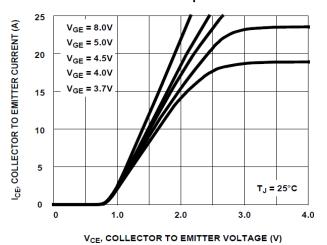


Figure 6. Collector to Emitter On- State Voltage vs. Collector Current

TYPICAL CHARACTERISTICS (continued)

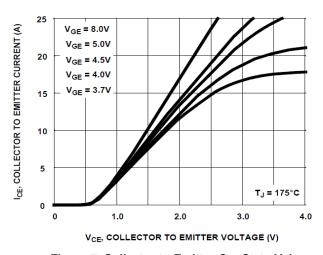


Figure 7. Collector to Emitter On–State Voltage vs. Collector Current

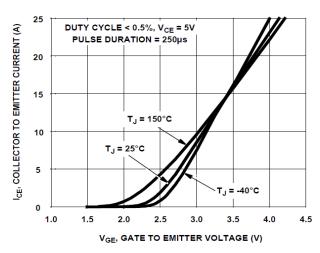


Figure 8. Transfer Characteristics

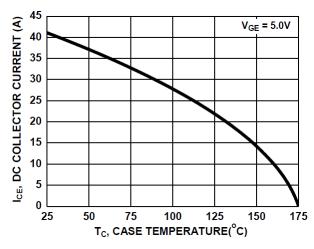


Figure 9. DC Collector Current vs. Case Temperature

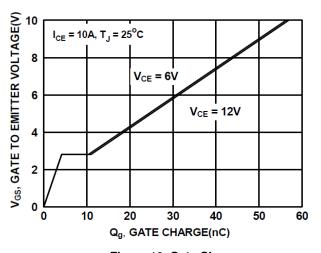


Figure 10. Gate Charge

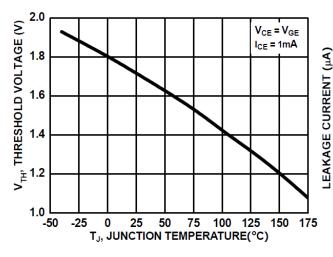


Figure 11. Threshold Voltage vs. Junction Temperature

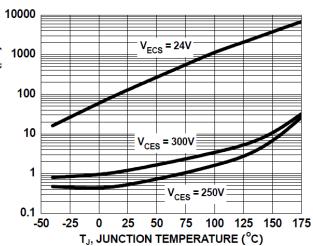


Figure 12. Leakage Current vs. Junction Temperature

TYPICAL CHARACTERISTICS (continued)

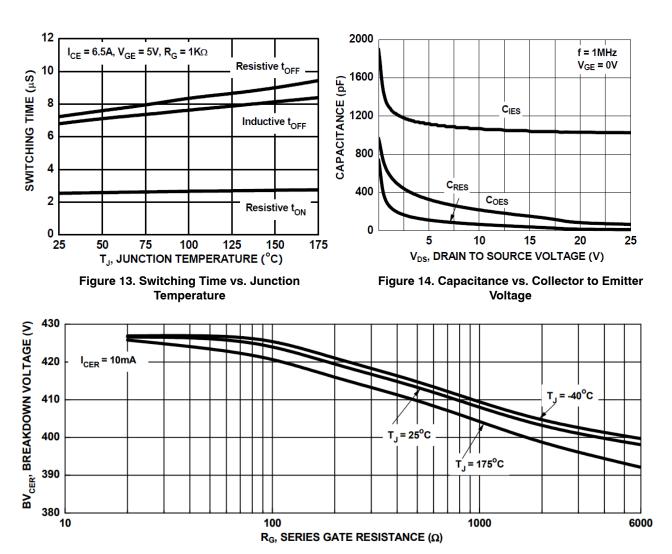


Figure 15. Break down Voltage vs. Series Resistance

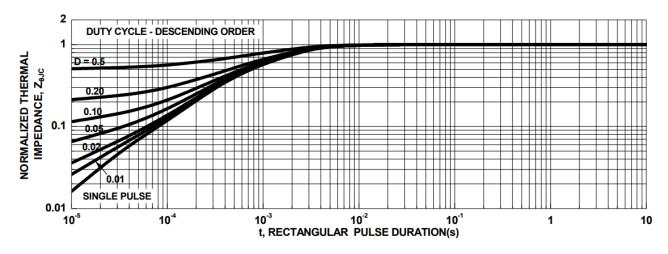
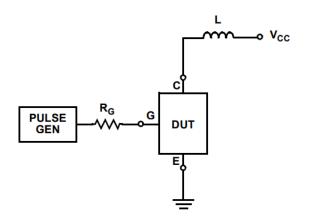


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case



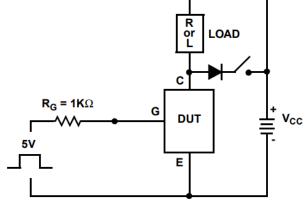


Figure 17. Inductive Switching Test Circuit

Figure 18. $t_{\mbox{\scriptsize ON}}$ and $t_{\mbox{\scriptsize OFF}}$ Switching Test Circuit

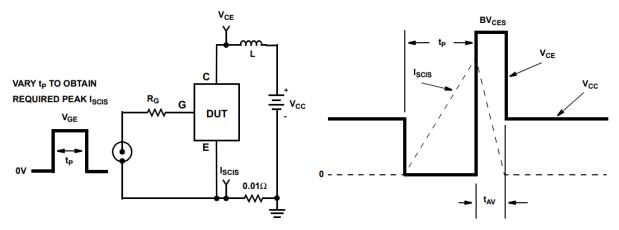


Figure 19. Energy Test Circuit

Figure 20. Energy Waveforms



A1

DETAIL A ROTATED 90° CW

DPAK (SINGLE GAUGE) CASE 369C

BOTTOM VIEW

ALTERNATE CONSTRUCTIONS

DATE 21 JUL 2015

- IOTES. 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

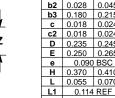
- MENSIONS b3, L3 and Z.

 Jimensions b And E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

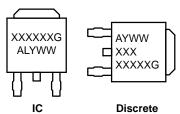
 MENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

 6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

	INC	INCHES MILLIMETERS		ETERS
DIM	MIN	MAX	MIN	MAX
Α	0.086	0.094	2.18	2.38
A1	0.000	0.005	0.00	0.13
b	0.025	0.035	0.63	0.89
b2	0.028	0.045	0.72	1.14
b3	0.180	0.215	4.57	5.46
С	0.018	0.024	0.46	0.61
c2	0.018	0.024	0.46	0.61
D	0.235	0.245	5.97	6.22
E	0.250	0.265	6.35	6.73
е	0.090 BSC		2.29	BSC
Н	0.370	0.410	9.40	10.41
L	0.055	0.070	1.40	1.78
L1	0.114	0.114 REF		REF
L2	0.020	BSC	0.51 BSC	
L3	0.035	0.050	0.89	1.27
L4		0.040		1.01
Z	0.155		3.93	



GENERIC MARKING DIAGRAM*

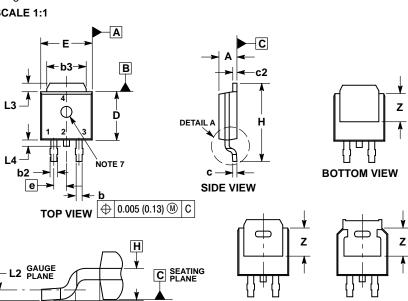


XXXXXX = Device Code

= Assembly Location Α = Wafer Lot L Υ = Year = Work Week WW G = Pb-Free Package

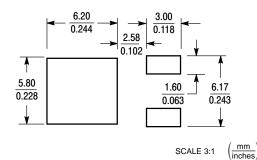
*This information is generic. Please refer to device data sheet for actual part marking.

ISSUE F



STYLE 1: PIN 1. BASE 2. COLLE 3. EMITTI 4. COLLE	ER 3.		STYLE 3: PIN 1. ANODI 2. CATHO 3. ANODI 4. CATHO	E DDE E	TYLE 4: PIN 1. CATHODE 2. ANODE 3. GATE 4. ANODE	STYLE 5: PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE
STYLE 6: PIN 1. MT1 2. MT2 3. GATE 4. MT2	STYLE 7: PIN 1. GATE 2. COLLEC 3. EMITTER 4. COLLEC	TOR 2	E 8: 1. N/C 2. CATHODE 3. ANODE 4. CATHODE	3. F		STYLE 10: PIN 1. CATHODE 2. ANODE T 3. CATHODE 4. ANODE

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

DOCUMENT NUMBER:	98AON10527D	Electronic versions are uncontrolle	'	
STATUS:	ON SEMICONDUCTOR STANDARD	accessed directly from the Document Repository. Printersions are uncontrolled except when stamped		
NEW STANDARD:	REF TO JEDEC TO-252	"CONTROLLED COPY" in red.		
DESCRIPTION:	DPAK SINGLE GAUGE SURFACE MOUNT		PAGE 1 OF 2	



DOCUMENT	NUMBER:
98AON10527	7D

PAGE 2 OF 2

ISSUE	REVISION	DATE
0	RELEASED FOR PRODUCTION. REQ. BY L. GAN	24 SEP 2001
А	ADDED STYLE 8. REQ. BY S. ALLEN.	06 AUG 2008
В	ADDED STYLE 9. REQ. BY D. WARNER.	16 JAN 2009
С	ADDED STYLE 10. REQ. BY S. ALLEN.	09 JUN 2009
D	RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE.	29 JUN 2010
E	ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAMBALIZA.	06 FEB 2014
F	ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA.	21 JUL 2015

ON Semiconductor and are registered trademarks of Semiconductor Components Industries, LLC (SCILLC). SCILLC reserves the right to make changes without further notice to any products herein. SCILLC makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does SCILLC assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. "Typical" parameters which may be provided in SCILLC data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. SCILLC does not convey any license under its patent rights nor the rights of others. SCILLC products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the SCILLC product could create a situation where personal injury or death may occur. Should Buyer purchase or use SCILLC products for any such unintended or unauthorized application, Buyer shall indemnify and hold SCILLC and its officers, employees, subsidiaries, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that SCILLC was negligent regarding the design or manufacture of the part. SCILLC is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT
North American Technical Support:
Voice Mail: 1 800-282-9855 Toll Free USA/Canada

Europe, Middle East and Africa Technical Support: a Phone: 00421 33 790 2910

Phone: 011 421 33 790 2910 For additional information, please contact your local Sales Representative